







SN74AHCT1G04-Q1

SCLS510B - JUNE 2003 - REVISED JANUARY 2023

SN74AHCT1G04-Q1 Automotive Single 4.5-V To 5.5-V Inverter With TTL-compatible **CMOS Inputs**

1 Features

- Qualified for automotive applications
- ESD protection exceeds 1500 V per MIL-STD-883, method 3015; exceeds 200 V using machine model (C = 200 pF, R = 0)
- Operating range of 4.5 V to 5.5 V
- Max tpd of 7.5 ns at 5 V
- Low power consumption, 10-µA max ICC
- 8-mA output drive at 5 V
- Inputs are TTL-voltage compatible

2 Applications

- Hybrid, Electric, and Powertrain Systems
- Advanced Driver Assistance Systems (ADAS)
- Body Electronics and Lighting
- Infotainment and Cluster

3 Description

The SN74AHCT1G04-Q1 contains one gate. The device performs the Boolean function Y = A.

Package Information

PART NUMBER	PACKAGE	BODY SIZE (NOM)				
SN74AHCT1G04-Q1	SOT-SC70	2.00 mm x 1.25 mm				





Table of Contents

1 Features1	8.1 Overview
2 Applications1	8.2 Functional Block Diagram
3 Description1	8.3 Feature Description
4 Revision History2	8.4 Device Functional Modes
5 Pin Configuration and Functions3	9 Application Information Disclaimer
6 Specifications4	9.1 Application Information
6.1 Absolute Maximum Ratings4	9.2 Typical Application
6.2 ESD Ratings4	9.3 Power Supply Recommendations10
6.3 Recommended Operating Conditions5	9.4 Layout10
6.4 Thermal Information5	10 Device and Documentation Support1
6.5 Electrical Characteristics6	10.1 Documentation Support1
6.6 Switching Characteristics, V _{CC} = 5 V ± 0.5 V6	10.2 Receiving Notification of Documentation Updates. 1
6.7 Operating Characteristics6	10.3 Support Resources1
6.8 Typical Characteristics6	10.4 Electrostatic Discharge Caution1
7 Parameter Measurement Information7	10.5 Glossary11
8 Detailed Description8	

4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision A (June 2003) to Revision B (January 2023)

Page



5 Pin Configuration and Functions

Figure 5-1. DCK Package Top View

NC - No internal connection

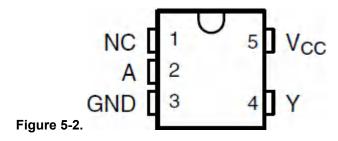


Table 5-1. Pin Functions

PIN		TYPE	DESCRIPTION		
NO.	NAME	ITPE	DESCRIPTION		
1	NC	_	No Connection		
2	A	I	Input A		
3	GND	_	Ground Pin		
4	Y	0	Output Y		
5	V _{CC}	_	Power Pin		



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		-0.5	7	V
VI	Input voltage range ⁽²⁾		-0.5	7	V
Vo	Output voltage range		-0.5 V	V _{CC} + 0.5 V	V
I _{IK}	Input clamp current	V _I < 0		-20	mA
I _{OK}	Output clamp current	$V_O < 0$ or $V_O > V_{CC}$		-20	mA
Io	Continuous output current	$V_{O} = 0$ to V_{CC}		±25	mA
	Continuous current through V _{CC} or GND			±50	mA
T _{stg}	Storage temperature		-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Section 6.3 is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
		Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	±1500	
V _(ESD)	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins ⁽²⁾	±1000	V

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

²⁾ The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.



6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(1)

		MIN ⁽¹⁾	MAX	UNIT
V _{CC}	Supply voltage	4.5	5.5	V
V _{IH}	High-level input voltage	2		V
V _{IL}	Low-level Input voltage		0.8	V
VI	Input voltage	0	5.5	V
Vo	Output voltage	0	V _{CC}	V
I _{OH}	High-level output current		-8	mA
I _{OL}	Low-level output current		8	mA
Δt/Δν	Input Transition rise or fall rate		20	ns/V
T _A	Operating free-air temperature	-40	125	°C

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs.

6.4 Thermal Information

	THERMAL METRIC ⁽¹⁾	DCK (SC70)	UNIT	
	I DERIVAL WEIRIO		ONIT	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	252	°C/W	

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

6.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V	T _A =	25°C		-40°C to +1	25°C	UNIT
PARAIVIETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	MIN	MAX	UNII
V	I _{OH} = -50 μA	4.5 V	4.4	4.5		4.4		V
V _{OH}	I _{OH} = -8 mA	4.5 V	3.94			3.8		v
V	I _{OL} = 50 μA	4.5 V			0.1		0.1	V
V _{OL}	I _{OL} = 8 mA	4.5 V			0.36		0.44	v
I _I	V _I = 5.5 V or GND	0 V to 5.5 V			± 0.1		±1	μA
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			1		10	μA
Δl _{CC} ¹	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			1.35		1.5	mA
C _i	V _I = V _{CC} or GND	5 V		4	10		10	pF

6.6 Switching Characteristics, $V_{CC} = 5 V \pm 0.5 V$

over recommended operating free-air temperature range (unless otherwise noted) (see load circuit and voltage wave forms)

PARAMETER	FROM	то	TEST	T,	_λ = 25°C		MIN	MAX	UNIT
FARAWETER	(INPUT)	(OUTPUT)	CONDITIONS	MIN	TYP	MAX	IVIIIV	WAX UNIT	UNIT
t _{PLH}	Α	Y	C _L = 15 pF		4.7 ⁽¹⁾	6.7 ⁽¹⁾	1	7.5	no
t _{PHL}	Α	Y	C _L = 15 pF		4.7 ⁽¹⁾	6.7 ⁽¹⁾	1	7.5	ns
t _{PLH}	Α	Y	C _L = 50 pF		5.5 ⁽¹⁾	7.7 ⁽¹⁾	1	8.5	ns
t _{PHL}	Α	Y	C _L = 50 pF		5.5	7.7	1	8.5	115

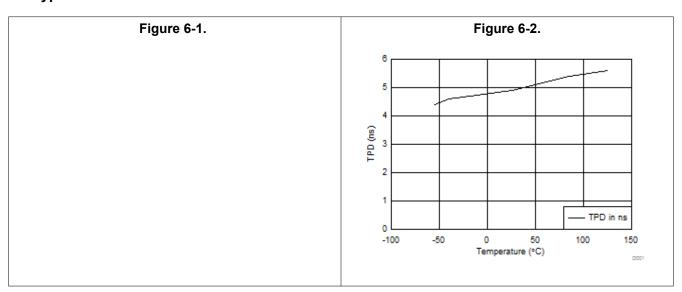
⁽¹⁾ On products compliant to MIL-PRF-38535, this parameter is not production tested.

6.7 Operating Characteristics

 $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$

PARAMETER		TES	TYP	UNIT	
C _{pd}	Power dissipation capacitance	No load,	f = 1 MHz	14	pF

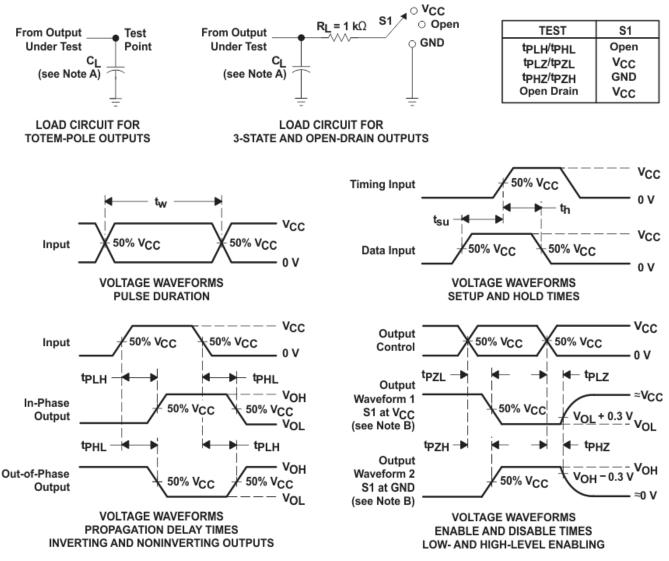
6.8 Typical Characteristics





7 Parameter Measurement Information

7.1



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z_O = 50 Ω, t_r ≤ 3 ns, t_f ≤ 3 ns.
- D. The outputs are measured one at a time, with one input transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpHL and tpLH are the same as tpd.
- H. All parameters and waveforms are not applicable to all devices.

Figure 7-1. Load Circuit and Voltage Waveforms

Copyright © 2023 Texas Instruments Incorporated

Submit Document Feedback

8 Detailed Description

8.1 Overview

The SN74AHCT1G04-Q1 contains one gate. The device performs the Boolean function Y = A.

8.2 Functional Block Diagram



8.3 Feature Description

- V_{CC} is optimized at 5 V
- Allows up voltage translation from 3.3 V to 5 V
 - Inputs accept V_{IH} levels of 2 V
- · Slow edge rates minimize output ringing
- Inputs are TTL-Voltage compatible

8.4 Device Functional Modes

Table 8-1. Function Table

INPUT	OUTPUT
Α	Y
Н	L
L	Н

Submit Document Feedback



9 Application Information Disclaimer

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

The SN74LV540A device is a low-drive CMOS device that can be used for a multitude of bus interface type applications where putput ringing is a concern. The low drive and slow edge rates will minimize overshoot and undershoot on the outputs. The inputs are tolerant to 5.5 V at any valid V_{CC} . This feature makes it Ideal for translating down to the V_{CC} level. Section 9.2.3 shows the reduction in ringing compared to higher drive parts such as AC.

9.2 Typical Application

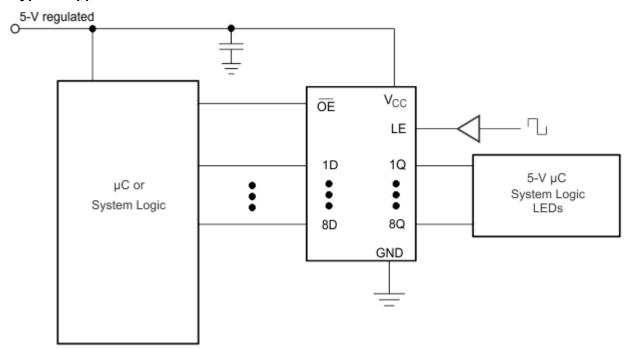


Figure 9-1. Typical Application Schematic

9.2.1 Design Requirements

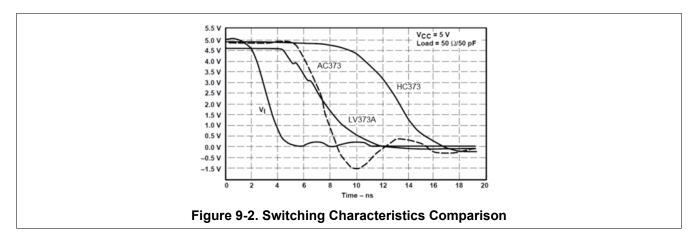
This device uses CMOS technology and has balanced output drive. Care should be taken to avoid bus contention because it can drive currents that would exceed maximum limits. The high drive will also create fast edges into light loads, so routing and load conditions should be considered to prevent ringing.

9.2.2 Detailed Design Procedure

- 1. Recommended Input Conditions
 - For rise time and fall time specifications, see Δt/ΔV in the Section 6.3 table.
 - For specified High and low levels, see V_{IH} and V_{IL} in the Section 6.3 table.
 - Inputs are overvoltage tolerant allowing them to go as high as 5.5 V at any valid V_{CC}.
- 2. Recommend Output Conditions
 - Load currents should not exceed 35 mA per output and 70 mA total for the part.
 - Outputs should not be pulled above V_{CC}.

Copyright © 2023 Texas Instruments Incorporated

9.2.3 Application Curves



9.3 Power Supply Recommendations

The power supply can be any voltage between the MIN and MAX supply voltage rating located in the Section 6.3 table.

Each V_{CC} pin should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, 0.1 μ F is recommended. If there are multiple V_{CC} pins, 0.01 μ F or 0.022 μ F is recommended for each power pin. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. A 0.1 μ F and 1 μ F are commonly used in parallel. The bypass capacitor should be installed as close to the power pin as possible for best results.

9.4 Layout

9.4.1 Layout Guidelines

When using multiple bit logic devices, inputs should not float. In many cases, functions or parts of functions of digital logic devices are unused. Some examples are when only two inputs of a triple-input AND gate are used, or when only 3 of the 4-buffer gates are used. Such input pins should not be left unconnected because the undefined voltages at the outside connections result in undefined operational states.

Specified in Section 9.4.2 are rules that must be observed under all circumstances. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that should be applied to any particular unused input depends on the function of the device. Generally they will be tied to GND or V_{CC} , whichever makes more sense or is more convenient. It is acceptable to float outputs unless the part is a transceiver. If the transceiver has an output enable pin, it will disable the outputs section of the part when asserted. This will not disable the input section of the I/Os so they also cannot float when disabled.

9.4.2 Layout Example

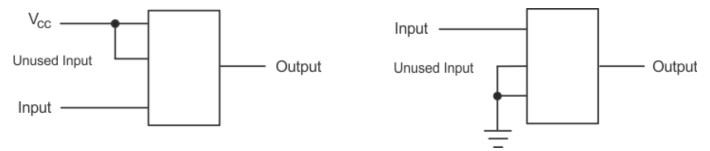


Figure 9-3. Layout Diagram



10 Device and Documentation Support

10.1 Documentation Support

10.1.1 Related Documentation

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

Table 10-1. Related Links

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY	
SN74AHCT1G04-Q1	Click here	Click here	Click here	Click here	Click here	

10.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Copyright © 2023 Texas Instruments Incorporated

www.ti.com 18-Jan-2023

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CAHCT1G04QDCKRG4Q1	ACTIVE	SC70	DCK	5	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	BCS	Samples
CAHCT1G04QDCKRQ1	ACTIVE	SC70	DCK	5	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	BCS	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE OPTION ADDENDUM

www.ti.com 18-Jan-2023

OTHER QUALIFIED VERSIONS OF SN74AHCT1G04-Q1:

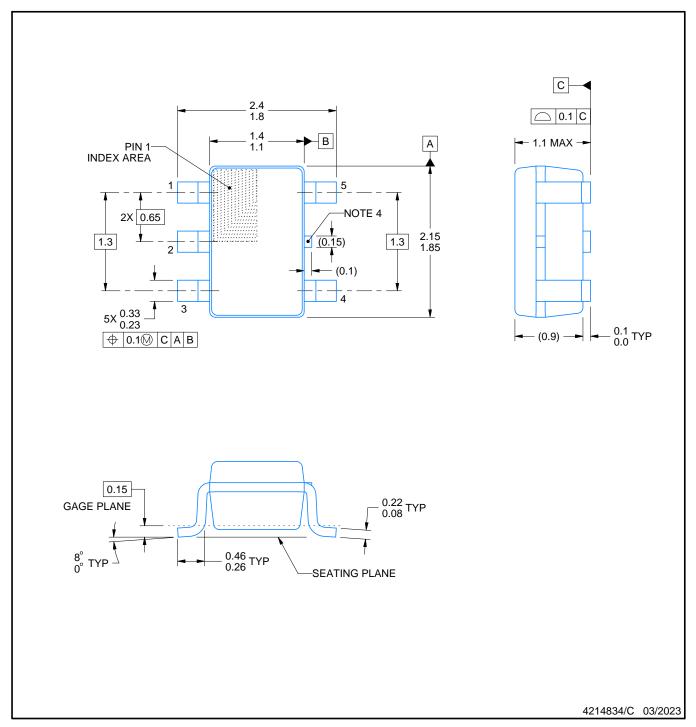
Catalog: SN74AHCT1G04

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product



SMALL OUTLINE TRANSISTOR



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

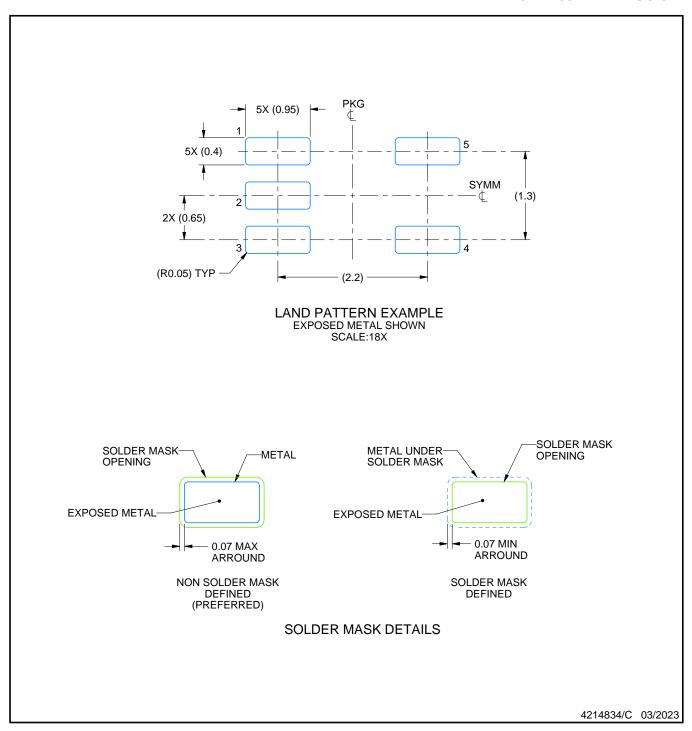
 2. This drawing is subject to change without notice.

 3. Reference JEDEC MO-203.

- 4. Support pin may differ or may not be present.



SMALL OUTLINE TRANSISTOR

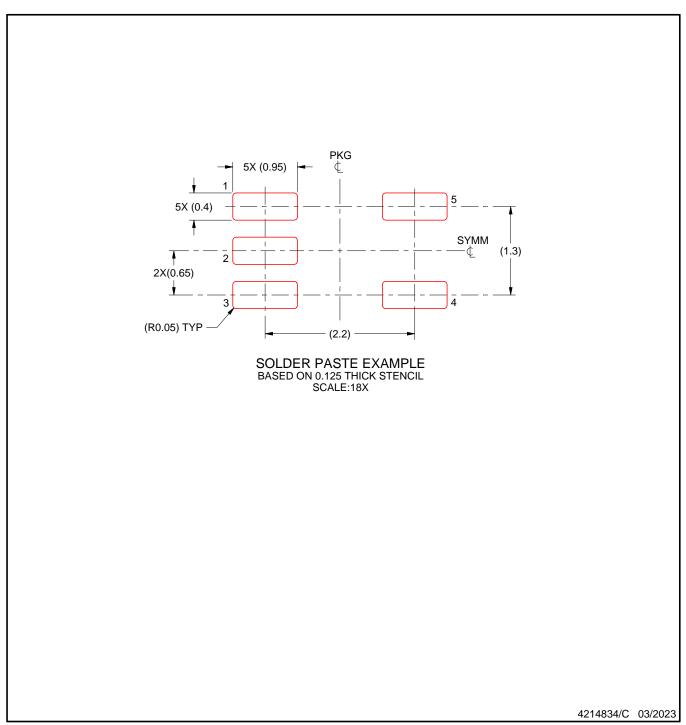


NOTES: (continued)

4. Publication IPC-7351 may have alternate designs.5. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE TRANSISTOR



NOTES: (continued)

- 6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 7. Board assembly site may have different recommendations for stencil design.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2023, Texas Instruments Incorporated